

- Multiple Internal level topology for low drive losses
- High-side drive capable with 3000 V isolation
- 5000 V Signal Isolation (up to 10 s)
- Capable of high gate currents with 3 W maximum power
- RoHS Compliant



## **Section I: Introduction**

The GA03IDDJT30-FR4 provides an optimized gate drive solution for SiC Junction Transistors (SJT). The board utilizes DC/DC converters and FOD3182 opto-isolators making it capable of driving high and low-side devices in a half-bridge configuration as well as IXDN609 gate driver ICs providing fast switching and customizable continuous gate currents necessary for SJT devices. Its footprint and 12 V supply voltage make it a plug-in replacement for existing SiC MOSFET gate drive solutions.



## **Section II: Compatibility with SiC SJTs**

The GA03IDDJT30-FR4 has an installed R<sub>G</sub> of 3.75  $\Omega$  on-board which may need to be modified by the user for safe operation of certain SJT parts. Please see the table below and Section VII for more information.





## **Section III: Operational Characteristics**



# **Section IV: Pin Out Description**



**Figure 2: Gate Drive Board Top View** 



### **Section V: SJT Gate Driving Theory of Operation**

ene:

MICONDUCTOR

The SJT transistor is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 3. This is similar to what the GA03IDDJT30-FR4 provides.

An SJT is rapidly switched on when the necessary gate charge, Q<sub>G</sub>, for turn-on is supplied by a burst of high gate current, I<sub>G,on</sub>, until the gatesource capacitance,  $C_{GS}$ , and gate-drain capacitance,  $C_{GD}$ , are fully charged.

$$
Q_{on} = I_{G,on} * t_1
$$
  

$$
Q_{on} \ge Q_{gs} + Q_{gd}
$$

The I<sub>G,pon</sub> pulse should ideally terminate, when the drain voltage falls to its on-state value, in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the  $I_{G,on}$  pulse is affected by the parasitic inductances,  $L_{par}$  in the device package and drive circuit. A voltage developed across the parasitic inductance in the source path, Ls, can de-bias the gate-source junction, when high drain currents begin to flow through the device. The applied gate voltage should be maintained high enough, above the  $V_{GS,ON}$  level to counter these effects.

After the SJT is turned on,  $I_G$  may be lowered to  $I_{G,steady}$  for reducing unnecessary gate drive power losses. The minimum  $I_{G,steady}$  is determined by noting the DC current gain,  $h_{FE}$ , of the device from its datasheet. The desired  $I_{G, steady}$  is determined by the peak device junction temperature  $T_J$  during operation, drain current I<sub>D</sub>, DC current gain  $h_{FE}$ , and a 50 % safety margin to ensure operating the device in the saturation region with low on-state voltage drop by the equation:

$$
I_{G,steady} \approx \frac{I_D}{h_{FE}(T,I_D)}*1.5
$$

For SJT turn -off, a high negative peak current, -I<sub>G,off</sub> at the start of the turn-off transition rapidly sweeps out charge from the gate. While satisfactory turn off can be achieved with V<sub>GS</sub> = 0 V, a negative gate voltage V<sub>GS</sub> may be used in order to speed up the turn-off transition. The GA03IDDJT30-FR4 provides a negative bias of -5 V during off state.



**Figure 3: Idealized SJT Gate Current Waveform** 

### **Section VI: Gate Driver Implementation**

The GA03IDDJT30-FR4 is a gate driver circuit which can be used to drive an SJT transistor by supplying the required gate drive current  $I_G$  in a low-power gate drive solution. This configuration features a gate capacitor C<sub>G</sub> (CG1 and CG2 in parallel) which creates a brief current peak I<sub>G,ON</sub> during device turn-on and I<sub>G,OFF</sub> during turn-off for fast switching and a gate resistor R<sub>G</sub> (RG1 and RG2 in parallel) to set the continuous gate current I<sub>G,steady</sub> required for an SJT to operate. This configuration is shown in the Figure 7 circuit diagram as well as in Figure 4 below with further details provided below. This section provides detail on selecting optimal  $C_G$  and  $R_G$  values based on the SJT, drain current, and temperature.



Figure 4: Primary gate drive circuit passive components with series gate resistance Schottky rectifier.





### **A: Gate Resistor RG Modification**

The GA03IDDJT30-FR4 on board gate resistor R<sub>G</sub> controls the continuous current I<sub>G,steady</sub> during steady on-state. The gate current is determined according to:

$$
I_{G,steady} = \frac{V_{GL} - V_{GS, sat} - V_D}{R_G + 0.6 \Omega}
$$

$$
I_{G, steady} = \frac{4.7 V - V_{GS, sat}}{R_G + 0.6 \Omega}
$$

Where  $V_{GL}$  is the internal, low-level drive voltage (5 V),  $V_{GS, sat}$  is the driven SJT saturated gate-source voltage obtained from the individual device datasheets,  $V_D$  is the Schottky diode voltage drop (approximately 0.3 V), and 0.6  $\Omega$  is added from internal GA03IDDJT30-FR4 drive components.

It is necessary for the user to reduce R<sub>G</sub> from its pre-install value of 3.75  $\Omega$  for several SiC SJTs for safe operation with the GA03IDDJT30-FR4 under high drain current conditions. The location of RG on the circuit board is shown in Figure 5. The maximum allowable value of R<sub>G</sub> for each device across all rated drain currents can be found in the Gate Drive section of each individual device datasheets.  $R_G$  may also be calculated from the following equation, where  $h_{FE}$  is the SJT DC current gain and  $V_{GS,sat}$  is the gate-source saturation voltage. Both of these values may be taken from individual device datasheets.

$$
R_{G,max} = \frac{(4.7V - V_{GS,sat}) * h_{FE}(T, I_D)}{I_D * 1.5} - 0.6\Omega
$$

For some devices and drain currents it may be desired for the user to install a very low value of R<sub>G</sub> or to short R<sub>G</sub> (R<sub>G</sub> = 0  $\Omega$ ) to increase the gate current output. This is acceptable, but may limit the duty cycle D during operation. Please see section VII:B for more information.

### **B: Duty Cycle Limitation**

The duty cycle *D* of the GA03IDDJT30-FR4 output may be limited by the 3 W power capability of the internal 5 V supply in some applications. If R<sub>G</sub> remains un-changed by the user I<sub>G steady</sub> will remain sufficiently low to allow 100 % duty cycle operation with an SJT. However, if R<sub>G</sub> is shorted or reduced such that  $R_G \le 2.8 \Omega$  in order to drive higher current devices, the duty cycle will be limited by the following equation:

$$
D \leq \frac{3W}{5V * I_{G,steady}} * 0.9
$$





**Figure 5: Location of RG (RG1 and RG2 in parallel) on GA03IDDJT30-FR4 driver for substitution** 

### **C: Gate Capacitor CG Modification**

An external gate capacitor  $C_G$  connected directly to the device gate pin delivers the positive current peak  $I_{GON}$  during device turn-on and the negative current peak I<sub>G,OFF</sub> during turn-off. A high value resistor R<sub>4</sub> in parallel with C<sub>G</sub> sets the SJT gate pin to a defined potential (-V<sub>EE</sub>) during steady off-state.

At device turn-on, C<sub>G</sub> is pulled to the GA03IDDJT30-FR4 internal voltage level V<sub>GH</sub> which produces a transient peak of gate voltage and current. This current peak rapidly charges the internal SJT C<sub>GS</sub> and C<sub>GD</sub> capacitances. A Schottky diode, D1, in series with R<sub>G</sub> blocks any C<sub>G</sub> induced current from draining out through  $R_G$  and ensures that all of the charge within  $C_G$  flows only into the device gate, allowing for an ultrafast device turn-on. During steady on-state, a potential of V<sub>GH</sub> - V<sub>GS =</sub> V<sub>GH</sub> - 3 V is across C<sub>G</sub>. When the device is turned off, C<sub>G</sub> is pulled to negative V<sub>EE</sub> and V<sub>GS</sub> is pulled to a transient peak of V<sub>GS,turn-off</sub> = V<sub>EE</sub> - (V<sub>GH</sub> - 3 V), this induces the negative current peak I<sub>G,off</sub> out of the gate which discharges the SJT internal capacitances.

### **D: Voltage Supply Selection**

The GA03IDDJT30-FR4 gate drive design features three internal supply voltages  $V_{GH}$ ,  $V_{GL}$ , and  $V_{EE}$  (listed in Table 4) supplied through two DC/DC converters. During device turn-on,  $V_{GH}$  charges the capacitor  $C_G$  thereby delivering the narrow width, high current pulse  $I_{GON}$  to the SJT gate and charges the SJT's internal terminal capacitances C<sub>GD</sub> and C<sub>GS</sub>. For a given level of parasitic inductance in the gate circuit and SJT package, the rise time of  $I_{G,ON}$  is controlled by the value of  $V_{GH}$  and  $C_G$ . During the steady on-state,  $V_{GL}$  in combination with the internal and external gate resistances provides a continuous gate current for the SJT to remain on. The  $V_{EE}$  supply controls the gate negative voltage during turn-off and steady off-state for faster switching and to avoid spurious turn-on which may be caused by external circuit noise. The power rating of the provided voltage supplies are adequate to meet the gate drive power requirements as determined by

$$
P_{min,VGH} = \frac{1}{2} C_G V_{GH}^2 f_{sw}
$$
  

$$
P_{min,VEE} = \frac{1}{2} C_G V_{EE}^2 f_{sw}
$$
  

$$
P_{min,VGL} = V_{GL} I_{G,steady} D
$$



### **Table 4: GA03IDDJT30-FR4 Gate Drive Voltage Supply Component List**

### **E: Voltage Supply Isolation**

The DC/DC supply voltage converters are suggested to provide isolation at a minimum of twice the working  $V_{DS}$  on the SJT transistor during off-state to provide adequate protection to circuitry external to the gate drive circuit. The installed DC/DC converters have an isolation of 3.0 kV and greater. Alternatively, DC/DC converter galvanic isolation may be bypassed and direct connection of variable voltage supplies may



be done in a laboratory environment, this may be convenient during testing and prototyping but carries risk and is not suggested for extended usage.



**Figure 6: Typical DC/DC converter configuration** 

### **F: Signal Isolation**

The gate supply signal is suggested to be isolated to twice the working  $V_{DS}$  on the SJT during off-state to provide adequate protection to circuitry external to the gate drive circuit. This may be done using opto or galvanic isolation techniques.



**Section VII: Detailed Schematic and Bill of Materials** 



**Figure 7: Gate Drive Board Detailed Block Diagram** 







## **Section VIII: Mechanical Drawing**







